


<b>Search Notes</b> 	<b>Application/Control No.</b> 10653021	<b>Applicant(s)/Patent Under Reexamination</b> LUO ET AL.
	<b>Examiner</b> Chawan, Sheela C	<b>Art Unit</b> 2624

SEARCHED			
Class	Subclass	Date	Examiner
382	117,167,165,275,164,103,274,118,199,173,162,190,115,	1/22/07	SCC
348	239,241,	"	"
396	191,198,	"	"
426	72,311,620,640,641,658	"	"

SEARCH NOTES		
Search Notes	Date	Examiner
EAST,US-PGPUB,USPAT,EPO,JPO,DERWENT, IBM-TDB.	1/22/07	SCC
INVENTOR NAME SEARCH.	"	"

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner